

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/694,218	<b>Applicant(s)/Patent under Reexamination</b> HIRANO, SHINTARO
	<b>Examiner</b> Tianjie Chen	<b>Art Unit</b> 2656

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
720	606	2/13/2006	TJ